

Development of X-ray Ionization Beam Position Monitor for PAL-XFEL Soft X-ray

September 14, 2023

HyoJung Hyun¹, Seonghan Kim¹, Sunmin Hwang¹,
Seungcheol Lee¹, Hoyoung Jang¹, Garam Hahn²

hjhyun@postech.ac.kr

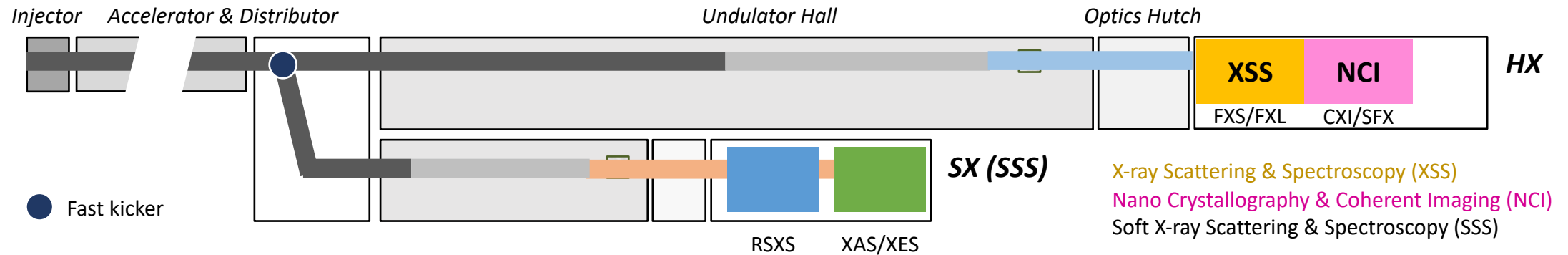
¹XFEL Beamline Division and ²PLS-II Accelerator Division
Pohang Accelerator Laboratory



Contents

- ◆ Introduction of PAL-XFEL
- ◆ X-ray Ionization Beam Position Monitor : Design, Manufacture & Assembly, Installation
- ◆ Test at PAL-XFEL Soft X-ray Beamline
- ◆ Simulation Study
- ◆ Summary and Plan

Introduction of PAL-XFEL



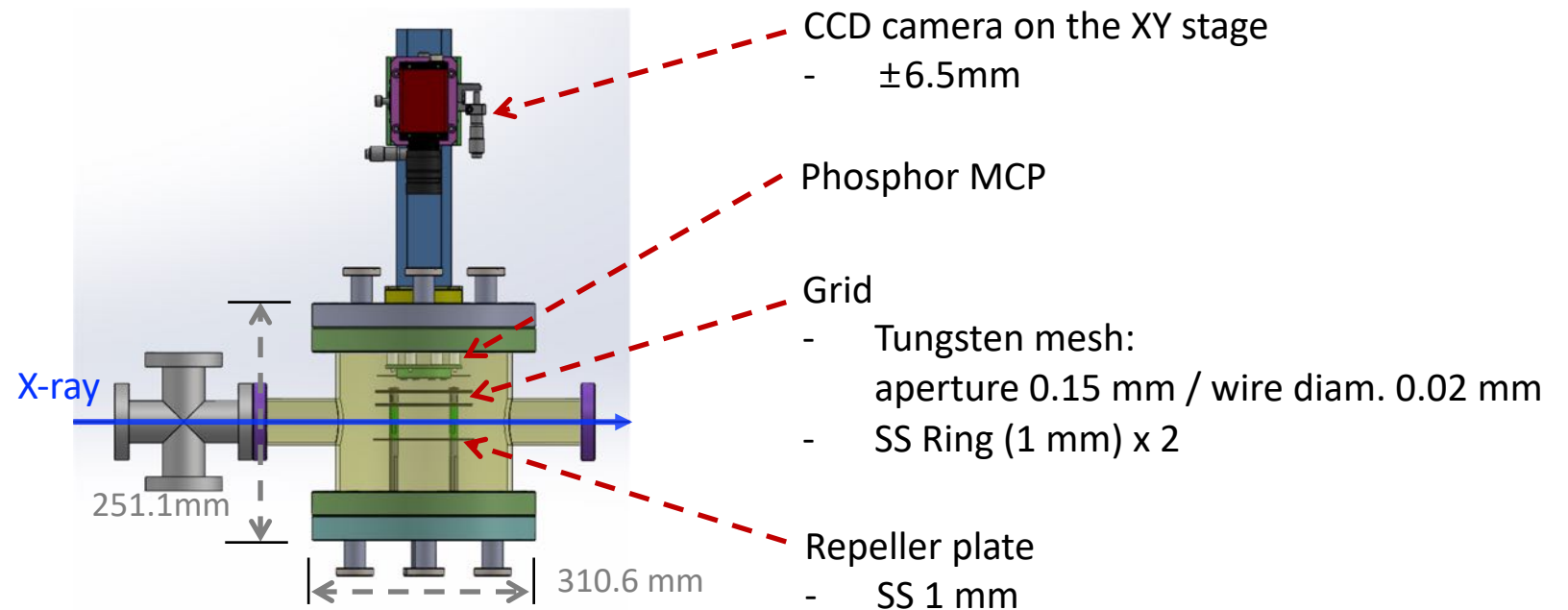
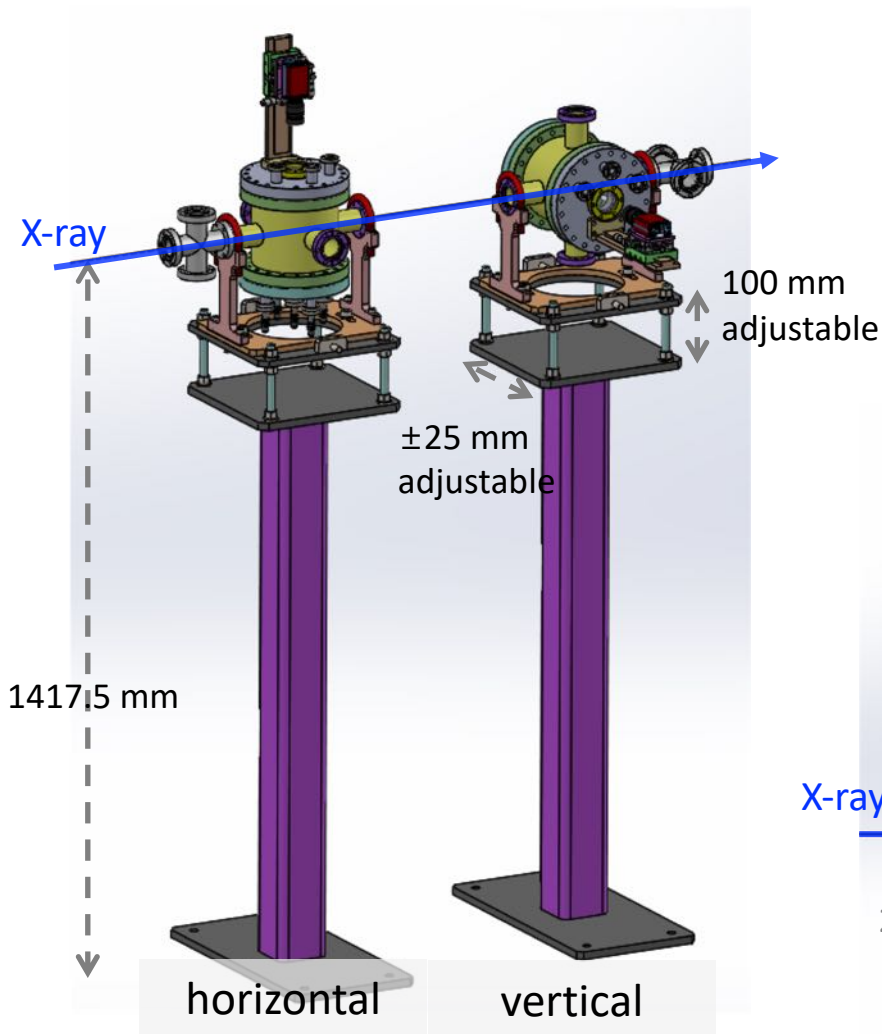
- ◆ The Pohang Accelerator Laboratory X-ray Free-Electron Laser (PAL-XFEL) is being operated
 - Provide intense ultrashort X-ray pulses based on the self amplified spontaneous emission (SASE) process
 - X-ray Free-Electron Laser (XFEL) is characterized by strong pulse-to-pulse fluctuations due to the SASE process
 - Online photon diagnostics are very important for the experiments

	Hard X-ray	Soft X-ray
Photon energy	2.0 ~ 15 keV (0.6 ~ 0.08 nm)	250 ~ 1250 eV (5 ~ 1 nm)
Repetition rate	10 Hz, 30 Hz, 60 Hz	10 Hz, 30 Hz, 60 Hz
Band width of pink beam ($\Delta E/E$)	~ 0.4 %	~ 0.5 %
Photon flux (pink beam)	$> 1.0 \times 10^{11}$ phs/pulse	$> 1.0 \times 10^{12}$ phs/pulse @ 800eV

X-ray Ionization Beam Position Monitor (XIBPM) : Design

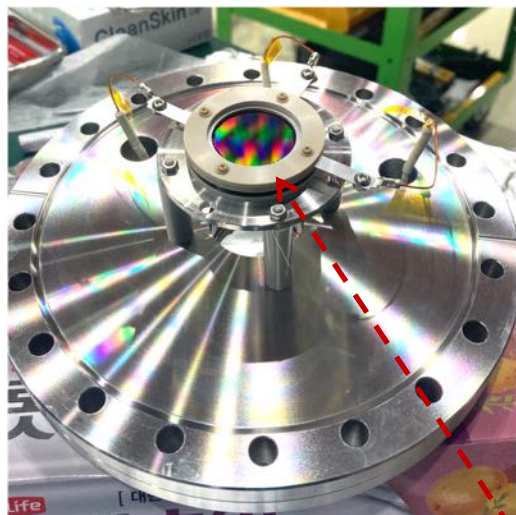
- ◆ To monitor the beam position at the soft X-ray beamline of the PAL-XFEL, a prototype **online X-ray ionization beam position monitor (XIBPM)** is developed

- Uses ionization of either residual gas in the vacuum or added Kr gas
- Photo-ions move following electric field, and are detected by microchannel plate (MCP) with phosphor screen and CCD camera

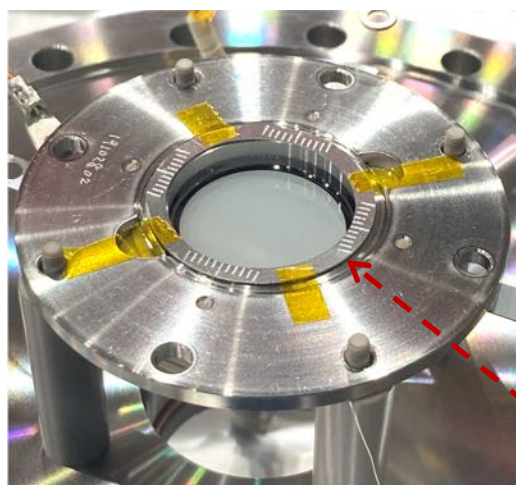


X-ray Ionization Beam Position Monitor (XIBPM) : Manufacture and Assembly

Detector side



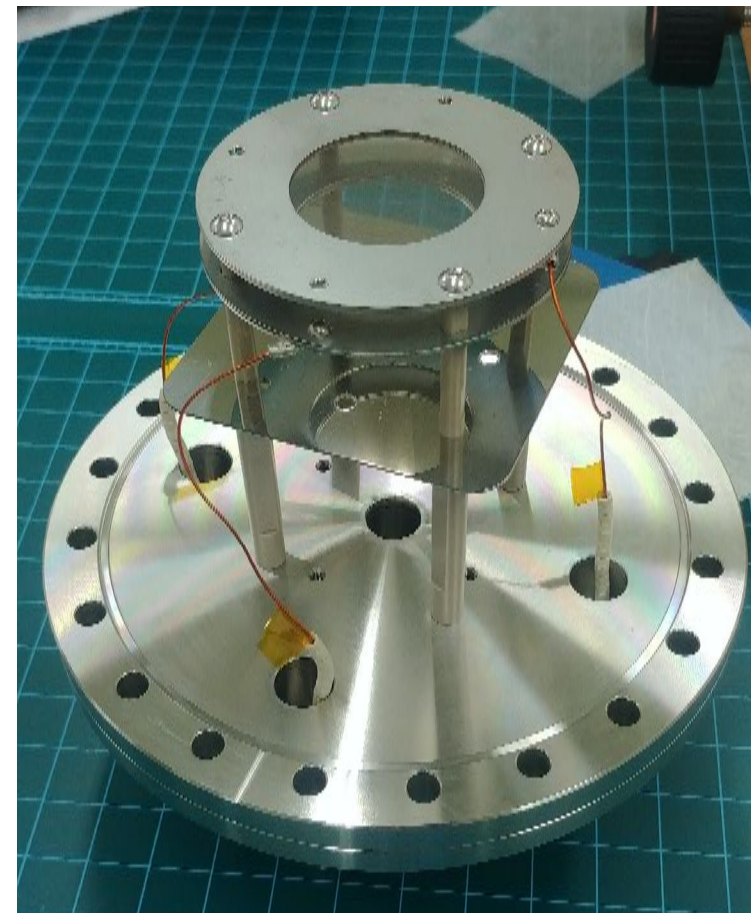
CCD camera with Lenz
(Manta G046)



Phosphor MCP
(F2223-21P including P43 Phosphor screen)

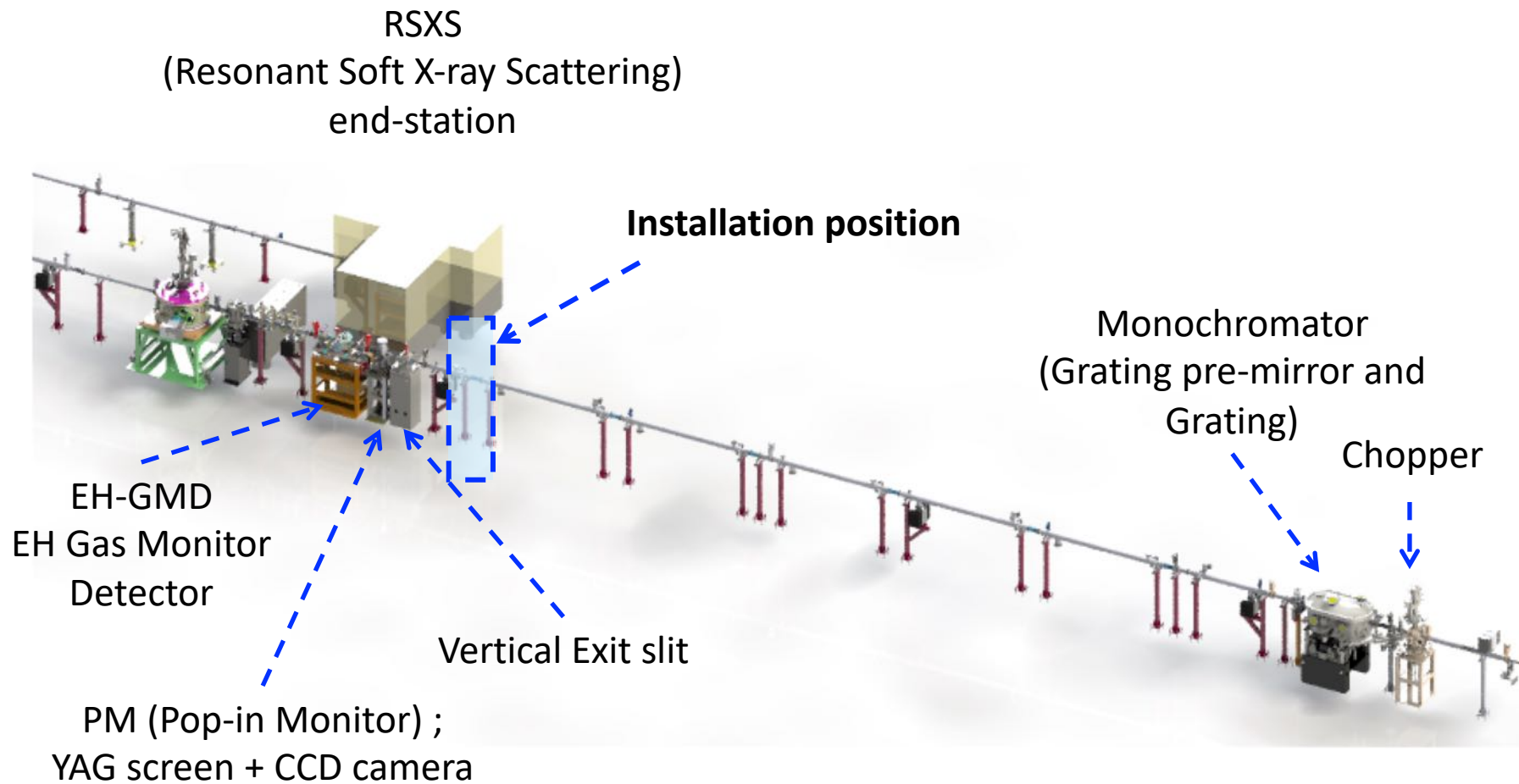
Ruller for calibration

E-field creation side



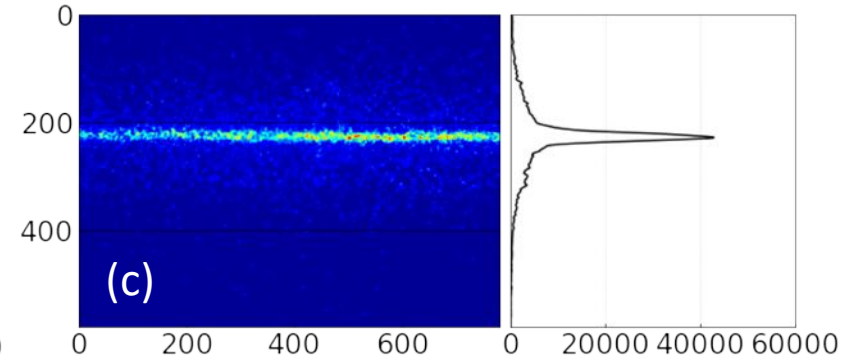
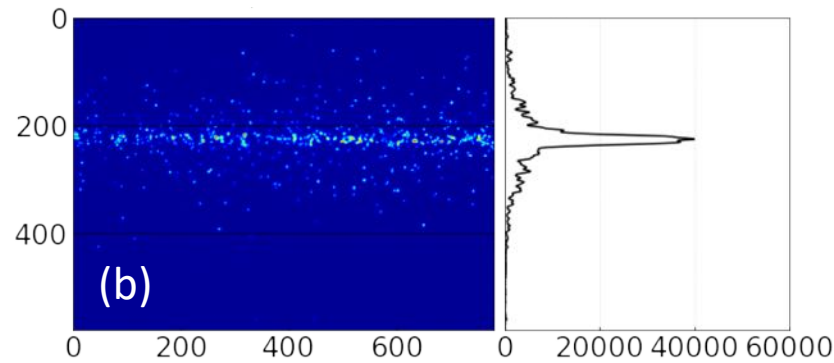
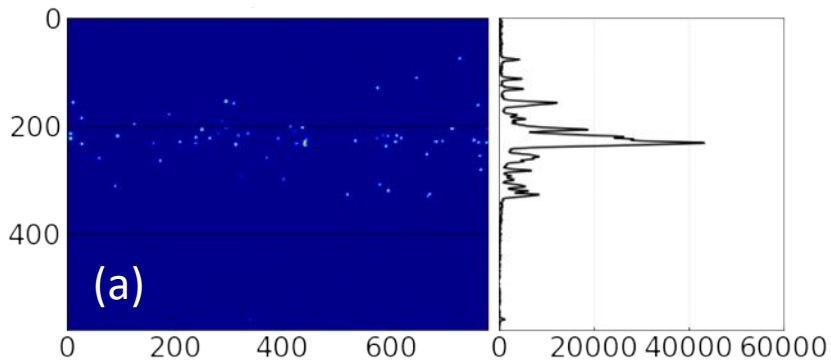
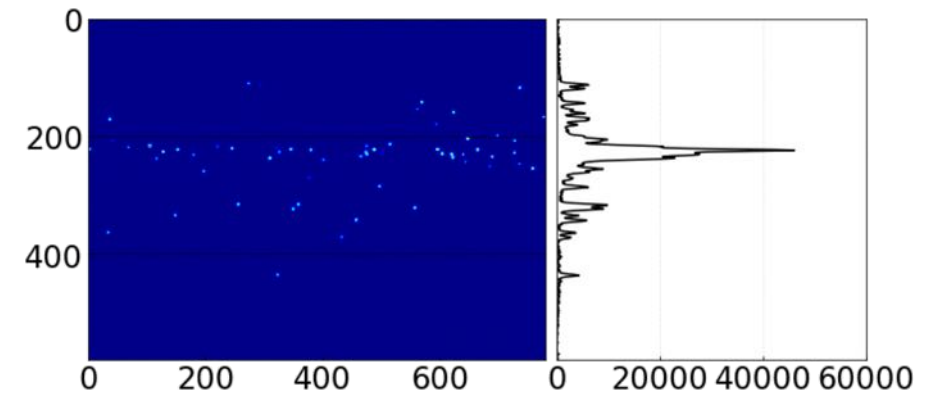
Tungsten mesh pairs and repeller plate
for electric field creation

X-ray Ionization Beam Position Monitor (XIBPM) : Installation



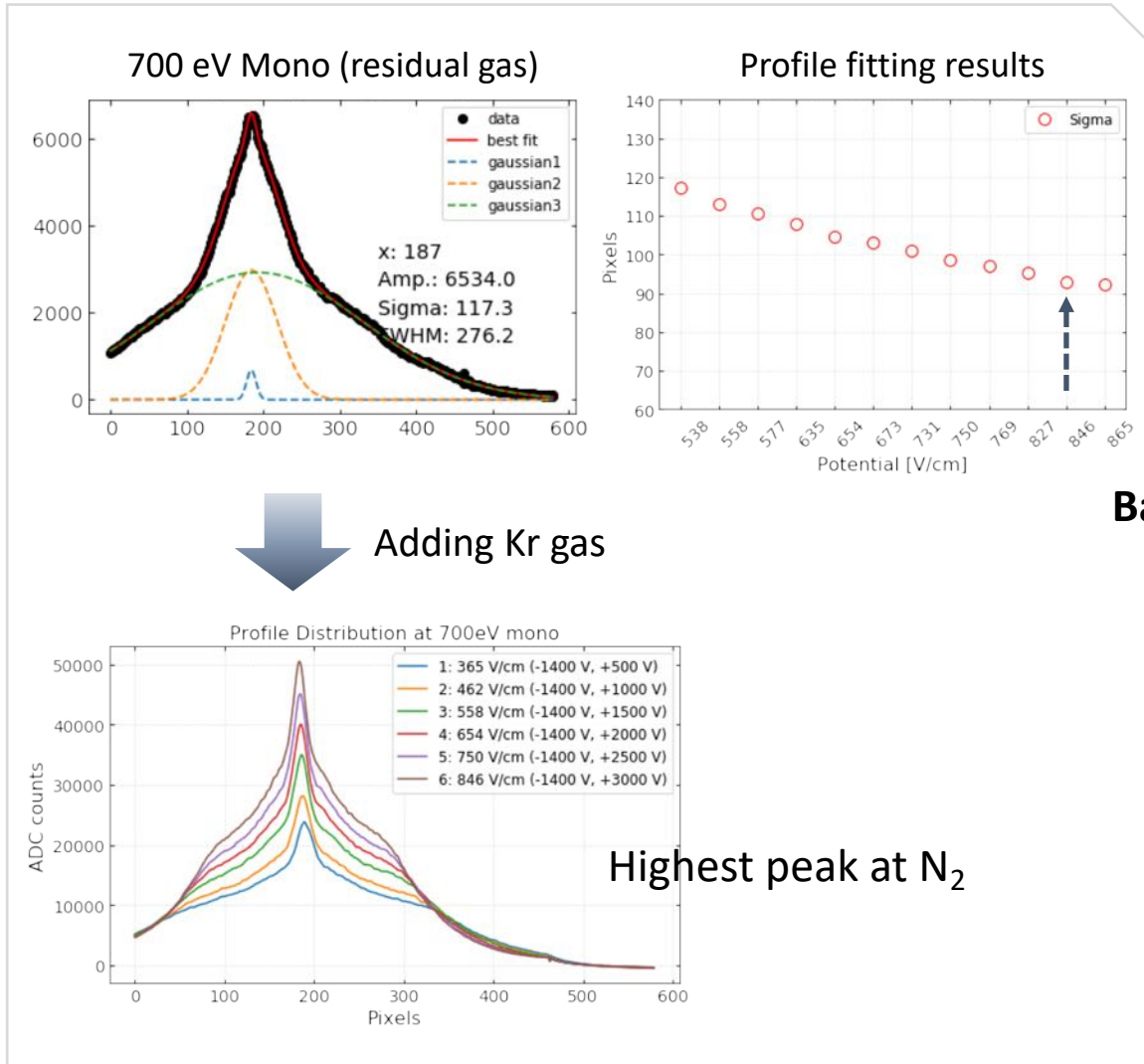
Tests at PAL-XFEL Soft X-ray Beamline

- ◆ The XIBPM was tested with various conditions as changing beam energy, electric field, MCP gain, and etc.
 - Pink and monochromatic X-ray : 500 eV – 1100 eV
 - Exit slit size in mono-beam mode : 0.2 mm, 1 mm
 - Residual gas mode (10^{-8} Torr) and Kr gas mode (10^{-6} Torr)
 - Grid (Mesh1 & Mesh2) voltage adjusted depending on voltages for MCP gain and Repeller plate

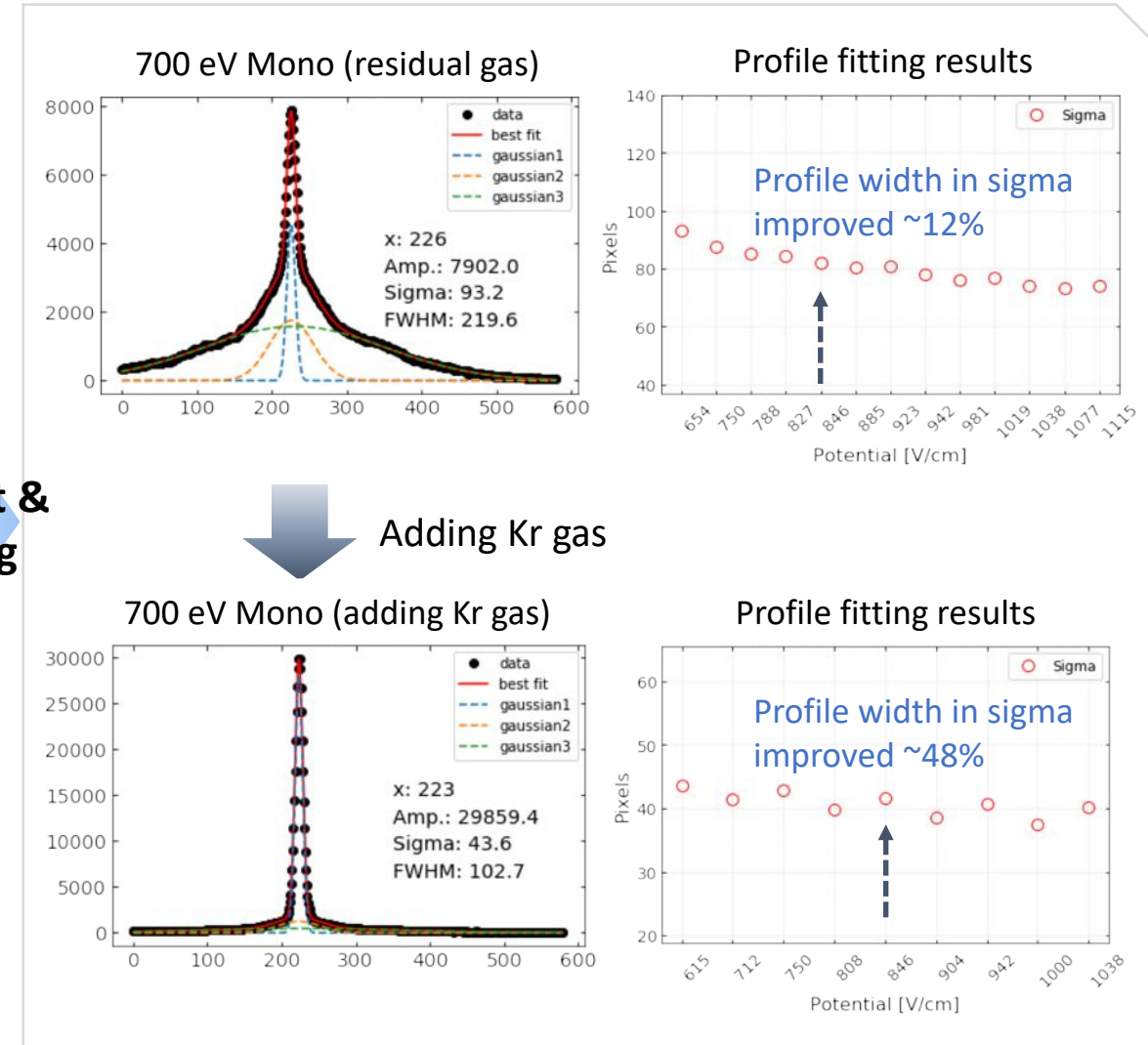


Trajectory of the beam at 500 eV mono-beam w/ 1 mm exit slit, residual gas mode, & E-field 885 V/cm : (a) one pulse, (b) 10 pulses averaged, and (c) 100 pulses averaged

Tests at PAL-XFEL Soft X-ray Beamline : Vacuum Quality Control



Bake-out & flushing

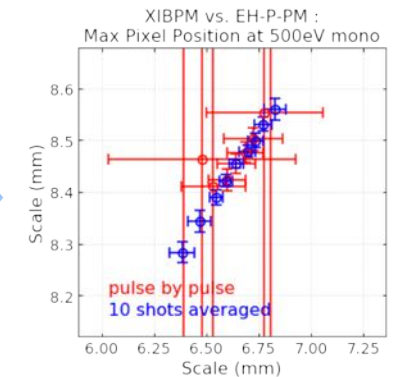
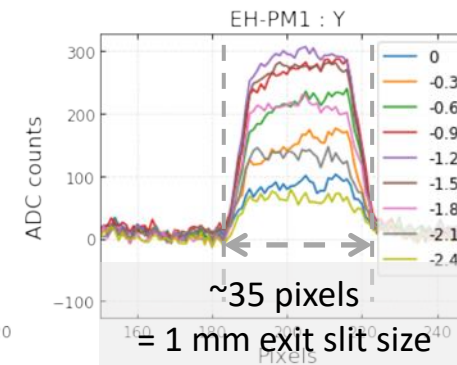
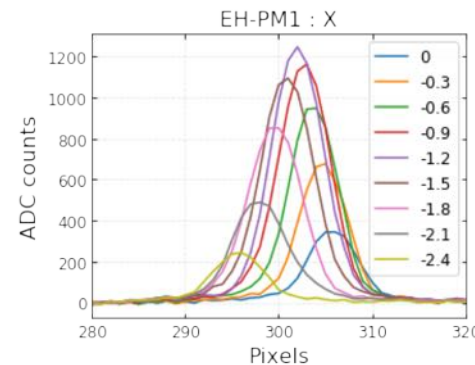
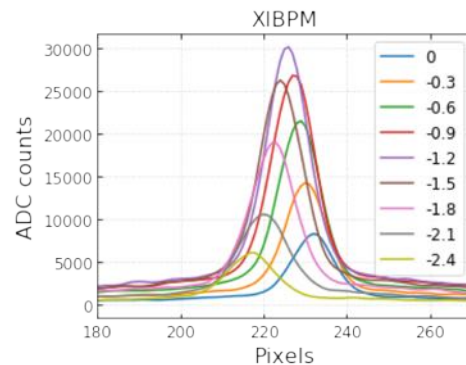


Tests at PAL-XFEL Soft X-ray Beamline : Displacement Comparison

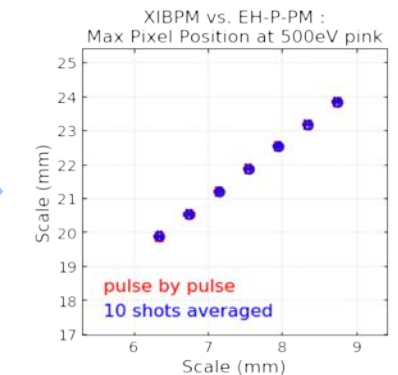
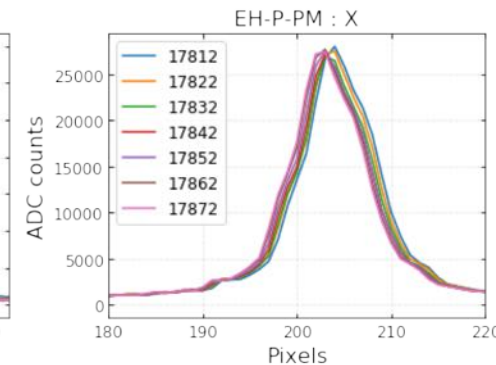
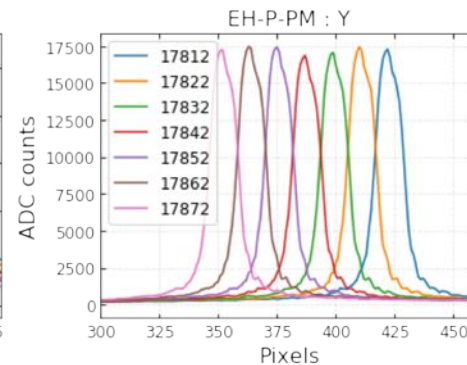
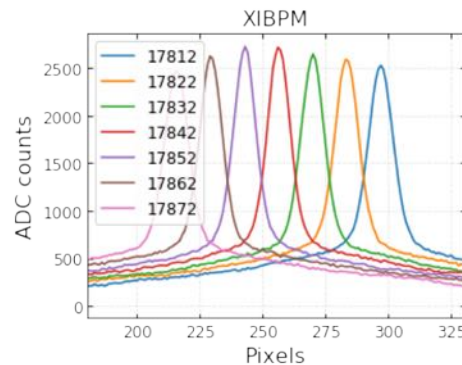
- ◆ Beam position change mimic
 - Horizontal : using chopper at mono-beam mode
 - Vertical : using grating pre-mirror at pink-beam mode

- For each step, data for 600 shots saved
- Each profile obtained via averaging 600 shots

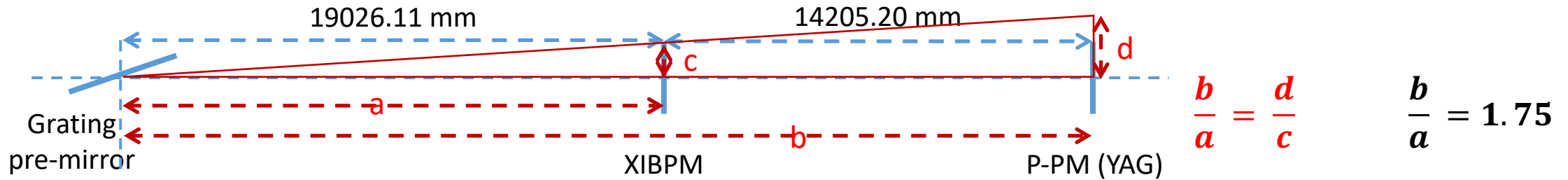
HORIZONTAL
500 eV Mono
Residual gas mode &
885 V/cm
(R +3000 V, G -1600 V)



VERTICAL
500 eV Pink
Residual gas mode &
885 V/cm
(R +3000 V, G -1600 V)



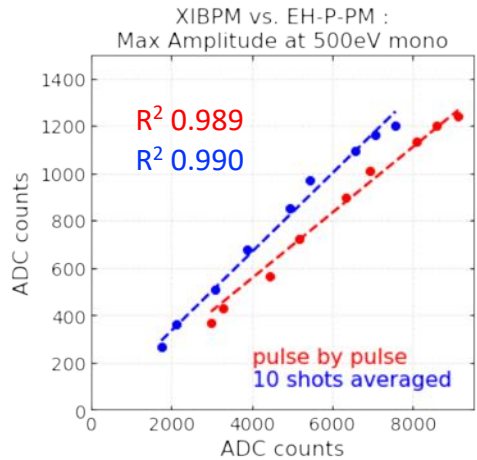
Tests at PAL-XFEL Soft X-ray Beamline : Displacement Comparison



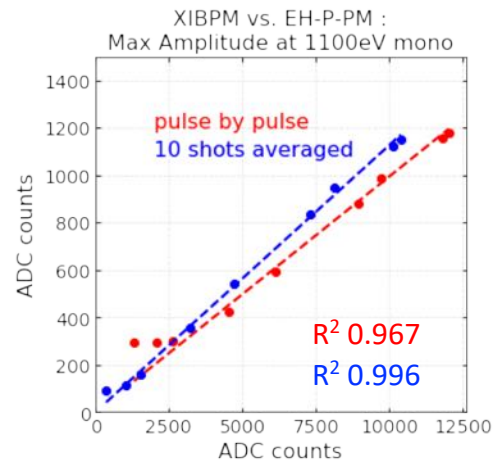
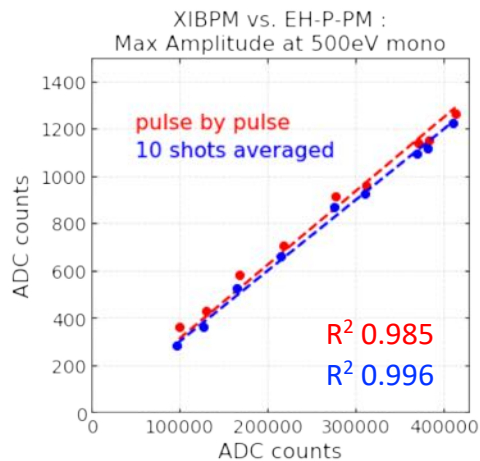
Ratio $\frac{d}{c}$ (relative % error)		864 V/cm (R +3000 V, G -1400 V)	885 V/cm (R +3000 V, G -1600 V)	923 V/cm (R +3000 V, G -1800 V)
500 eV Pink	Shot-to-shot	1.86 (6.29 %)	1.66 (5.14 %)	1.67 (4.57 %)
	Every 60 shots averaged	1.66 (5.14 %)	1.66 (5.14 %)	1.66 (5.14 %)
	All shots averaged	1.64 (6.29 %)	1.66 (5.14 %)	1.66 (5.14 %)
900 eV Pink	Shot-to-shot	3.73 (113 %)	1.63 (6.86 %)	1.67 (4.57 %)
	Every 60 shots averaged	1.65 (5.71 %)	1.66 (5.14 %)	1.65 (5.71 %)
	All shots averaged	1.66 (5.14 %)	1.62 (7.43 %)	1.62 (7.43 %)

Tests at PAL-XFEL Soft X-ray Beamline : Linearity

Residual gas mode & 846 V/cm
(R +3000 V, G -1400 V)

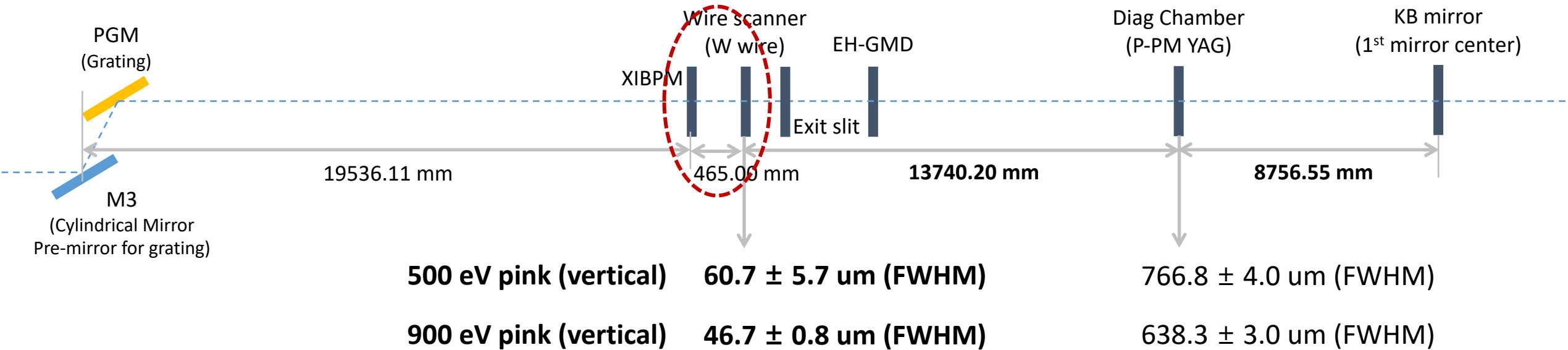


Kr gas mode & 846 V/cm
(R +3000 V, G -1400 V)



- ◆ From the chopper scan data, linearity of the XIBPM could be checked
 - The data points are obtained by either averaging maximum amplitude of pulse by pulse or averaging every 10 pulses' profile grouped
 - ✓ They are fitted using linear function ; $y = ax$
 - At 700 eV and 900 eV mono-beams, PM shows saturation feature
 - At 500 eV and 1100 eV mono-beams, XIBPM and PM shows linear correlation

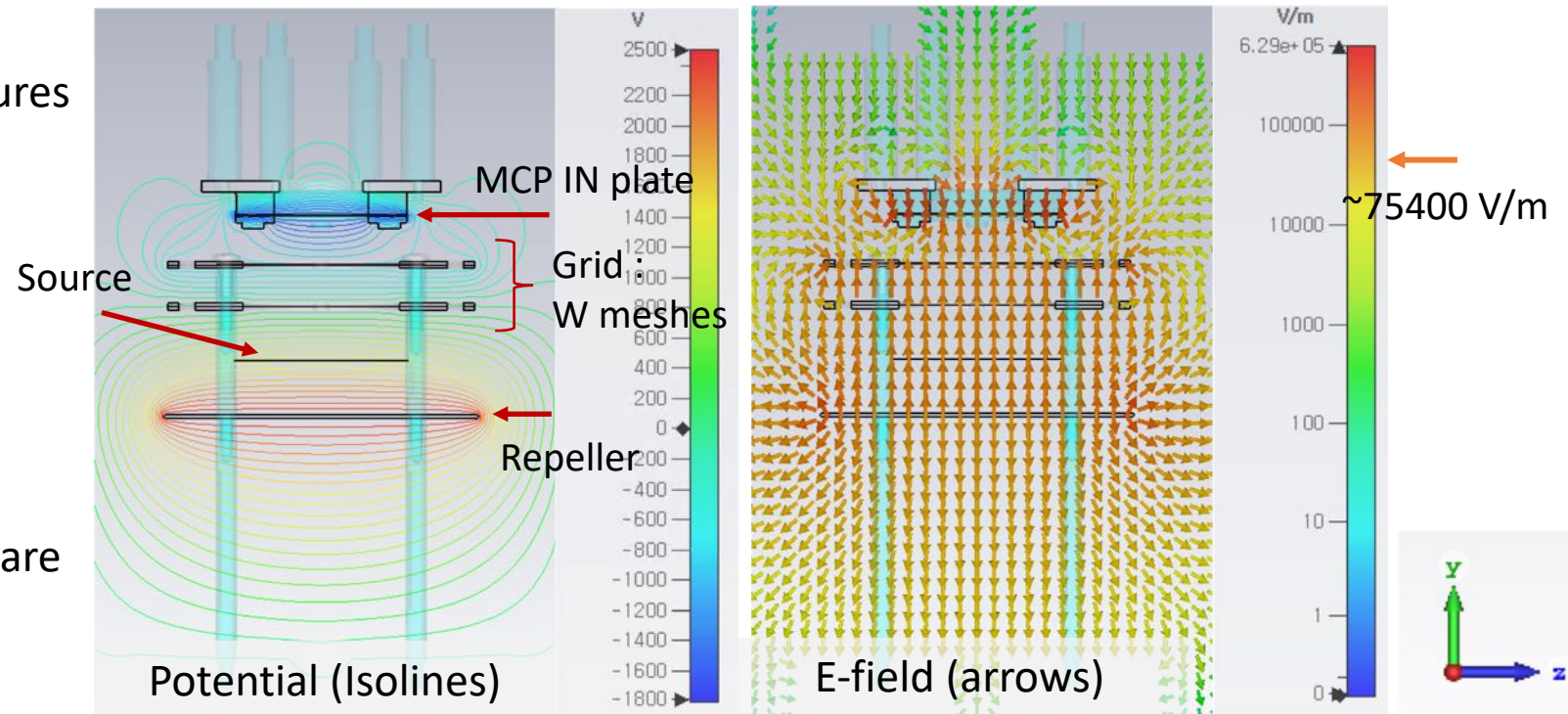
Tests at PAL-XFEL Soft X-ray Beamline : Beam Size Estimation from Profile Width



- ◆ Wire scanner with W wires of 500 μm & 200 μm diameters is recently installed just before the exit slit
- ◆ We could compare width of the Y profile obtained from the XIBPM and beam size measured by knife edge method via wire scanner
- ◆ The widths of the XIBPM's Y profile at the residual gas mode are about 7 times and 20 times larger than beam size measurement results for 500 eV pink and 900 eV pink beams, respectively

Simulation Study

- ◆ Electrostatic field-map of the XIBPM and multiparticle tracking studies on the obtained filed-map is ongoing **using the CST (Computer Simulation Technology) Studio Suite**
 - To quantitatively analyze and identify error components such as a non-flat mesh electrodes or protruded connectors for the potential setup, in order to improve a measurement precision
- ◆ Ideal case
 - No miss-aligned between structures
 - W meshes in Grid so flat
 - No lead for MCP IN plate
 - Almost equipotential
→ R +2500 V, G -1800 V
- ◆ Source is assumed to be Kr^{1+} ion in a cylinder of 1 μm radius, and Kr^{1+} ions are in rest at the source point

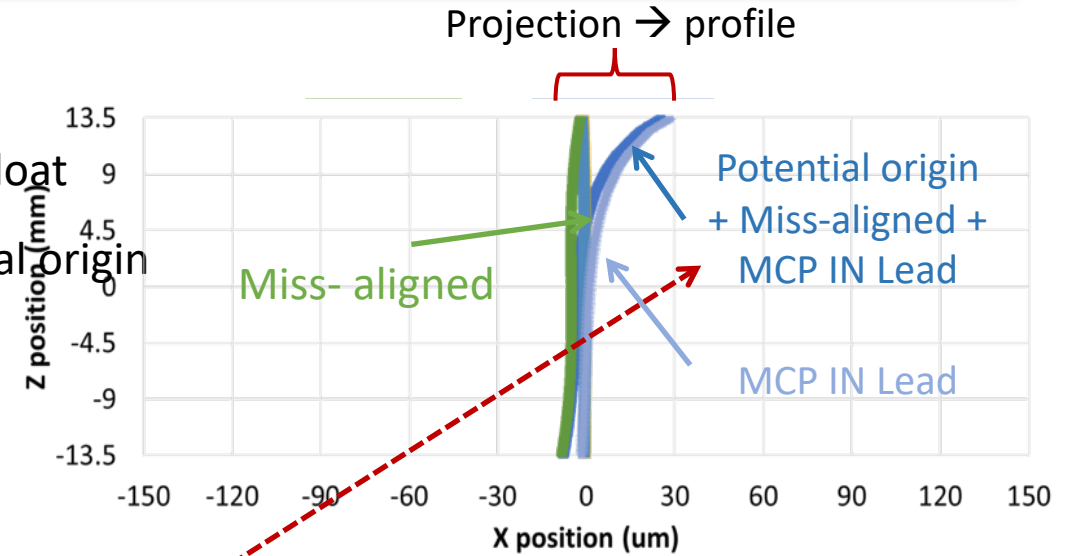
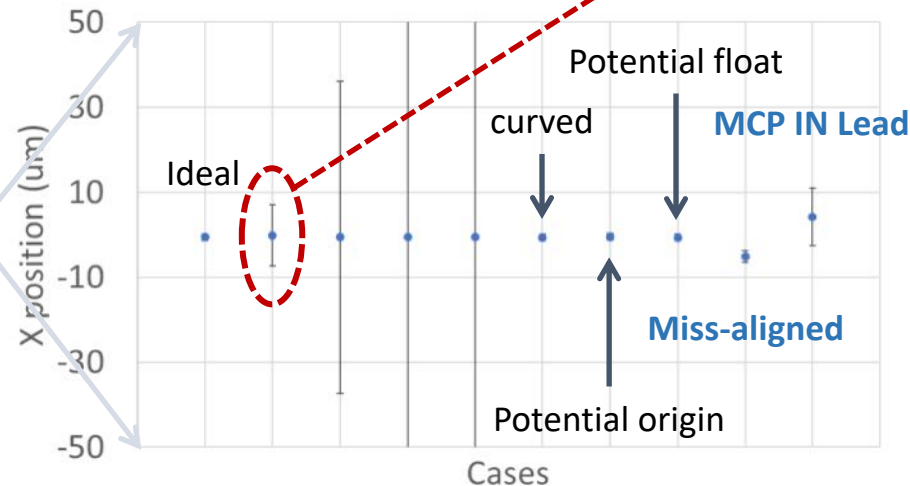
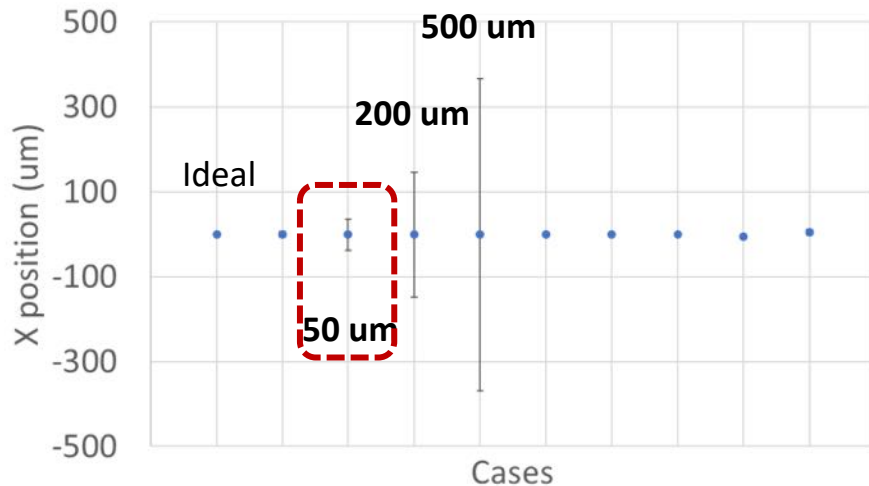


Simulation Study

◆ From the Ideal case

Beam size:
1 μm
in radius

- Voltages not applied to W meshes of the grid → Potential float
- Wrong voltages applied to W meshes of the grid → Potential origin
- **Structure slightly miss-aligned → Miss-aligned**
- One of the W meshes not flat → Curved
- **Make a lead for MCP IN plate → MCP IN Lead**
- Source size increased to be 50 μm , 200 μm , and 500 μm

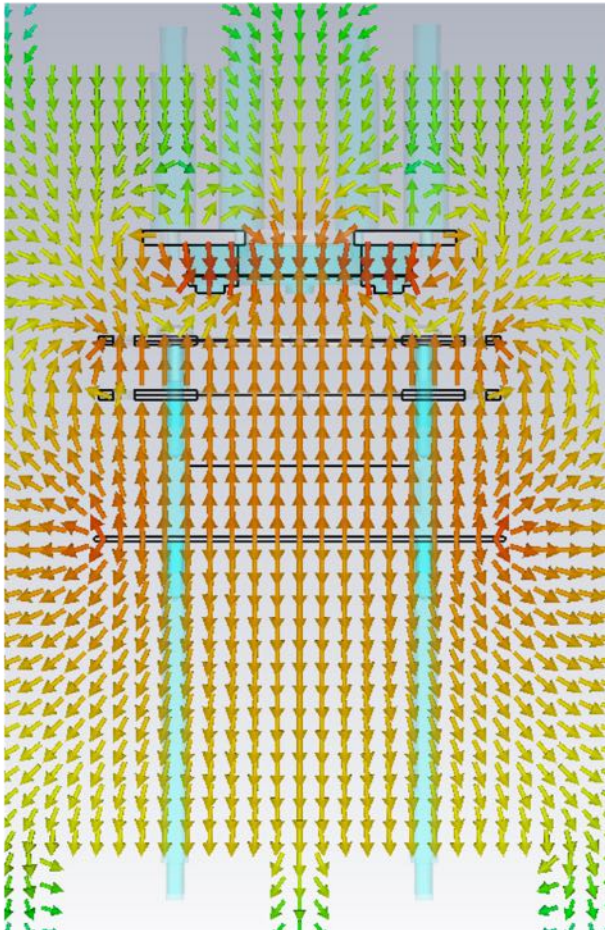


→ about 88 μm in FWHM

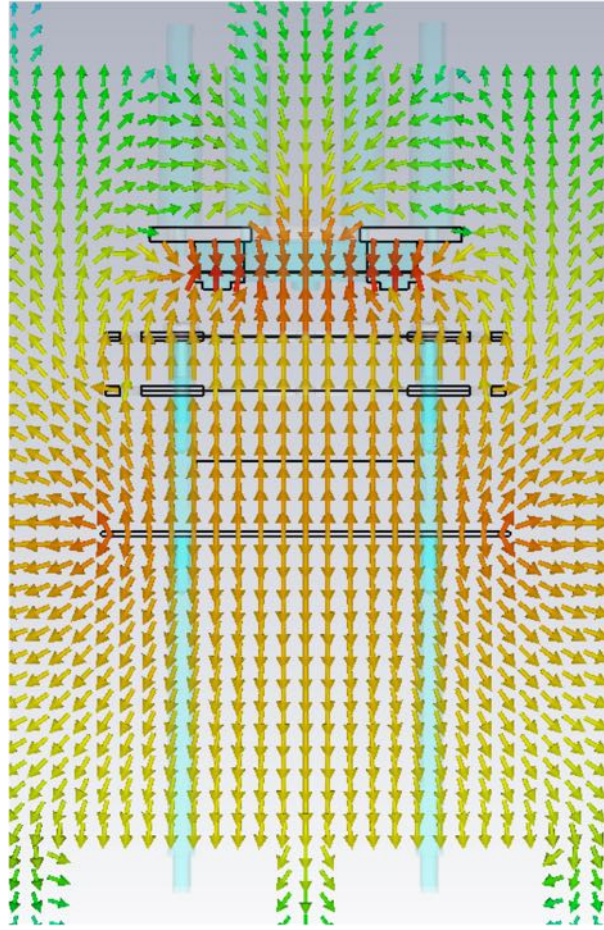
Simulation is ongoing about source variations such as $>\text{Kr}^{2+}$ and N^{n+} , and including kinetic energy of the photo-ions

Simulation Study : Electric Field Distributions

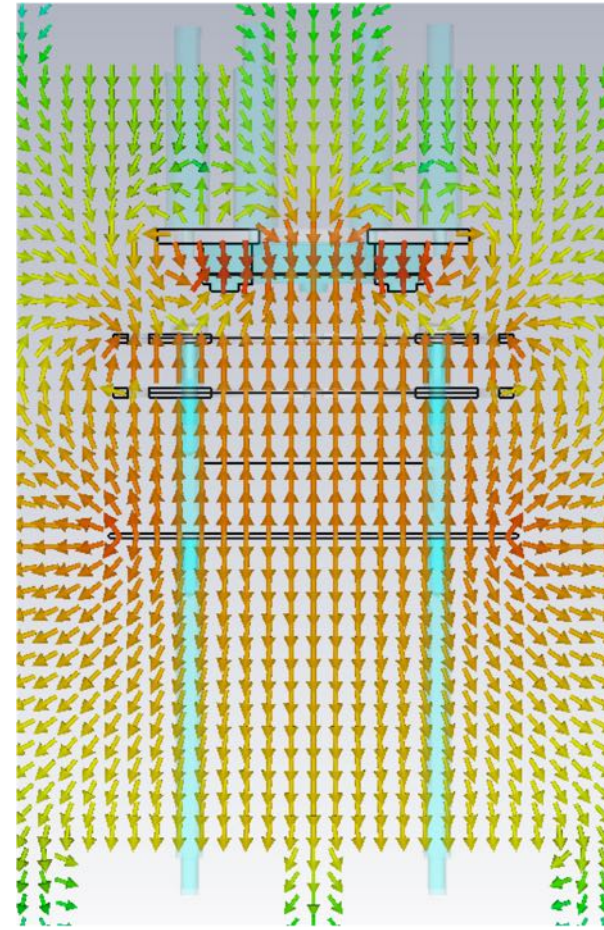
Ideal



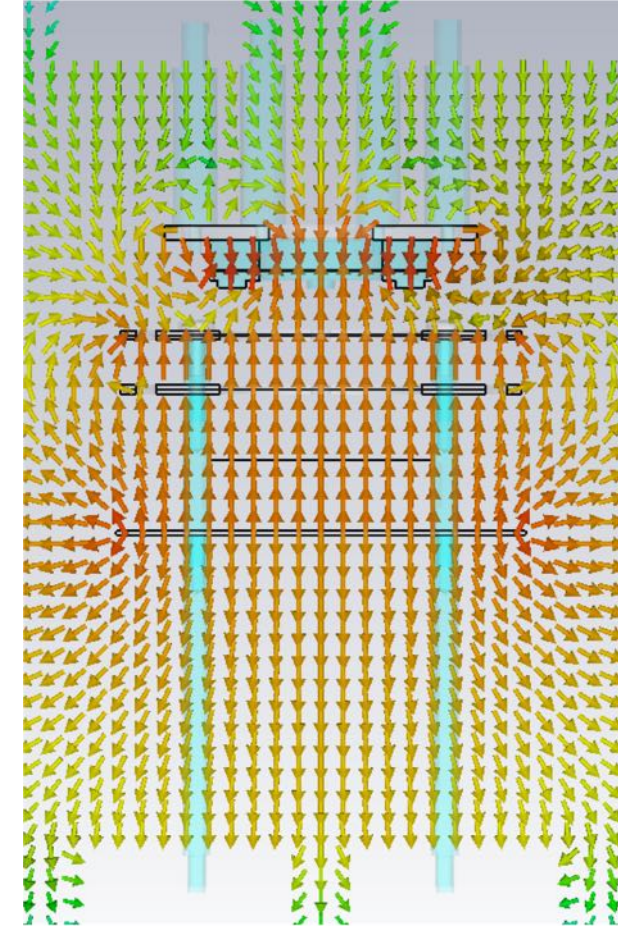
Potential float



Miss-aligned



MCP IN Lead

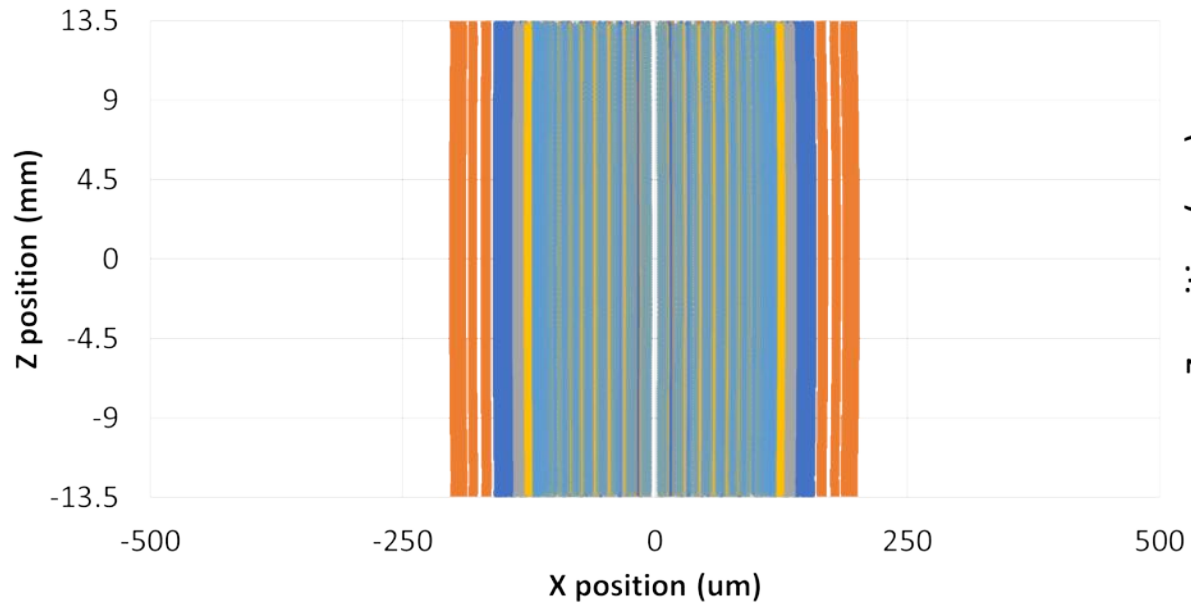


Simulation Study : Example - Source Variations

$\text{Kr}^{1+ \sim 5+}$

(K.E. 0.01 eV with energy spread 0 %)

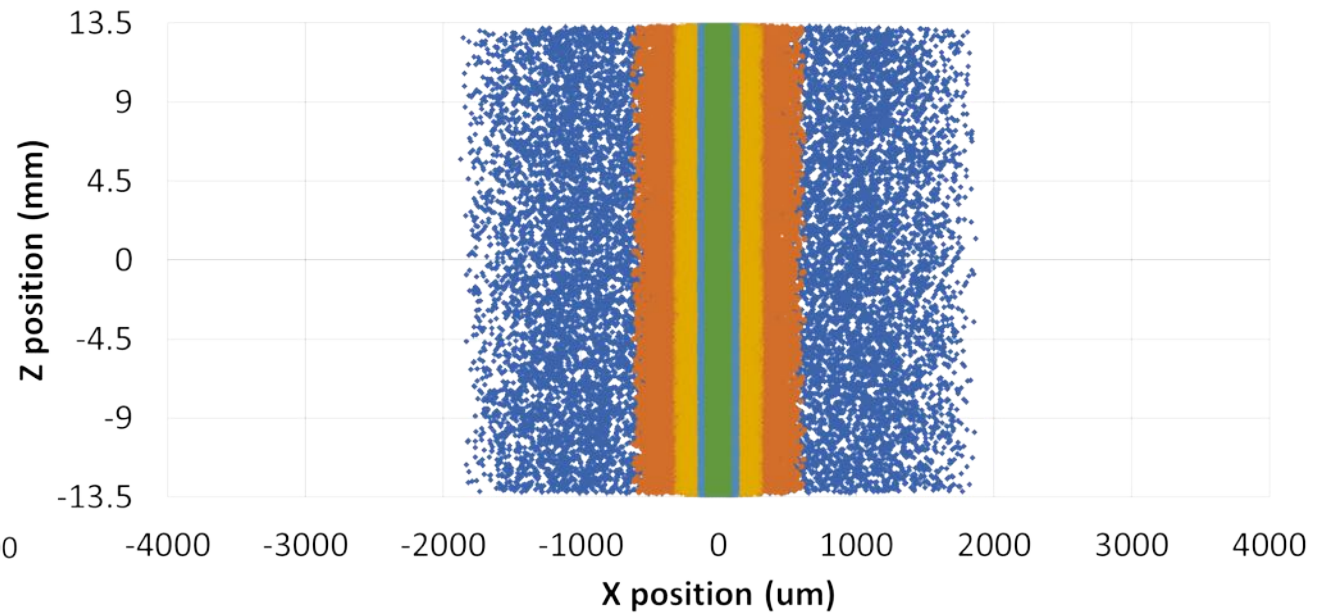
• Kr1+ • Kr2+ • Kr3+ • Kr4+ • Kr5+



$\text{N}^{1+, 5+}$

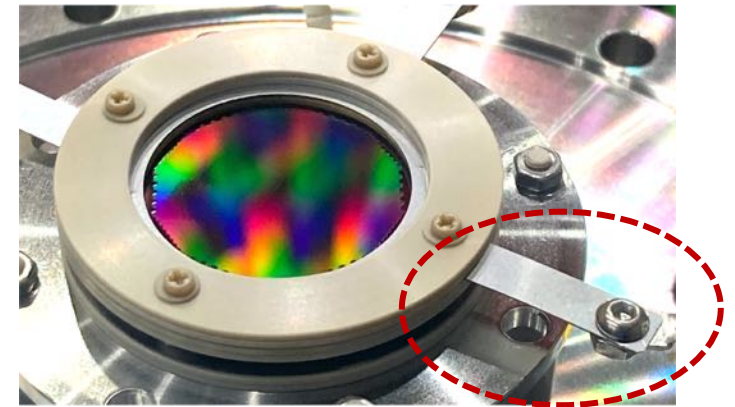
(with energy spread 100 %)

• N1+ 1 eV • N1+ 0.1 eV • N1+ 0.01 eV
• N5+ 0.1eV • N5+ 0.01eV • N5+ 0.001eV



Summary and Plan

- ◆ The XIBPM using ionization of residual gas or added Kr and the MCP with phosphor screen developed
 - ◆ The XIBPM was tested using soft X-ray FEL beams
 - Trajectory of the beam was detected apparently
 - The change of the beam center position was also measured
 - ◆ The particle tracking study was done to figure out field error sources
 - MCP In plate's lead is most significant systematic error component
-
- ◆ The simulation with various source condition will be followed
 - ◆ And also, additional test of the XIBPM at PAL-XFEL soft X-ray beamline is scheduled in next week
 - ◆ The length of the lead will be made shorten to improve the performance



Acknowledgements

Diagnostic group at PAL-XFEL:

Seonghan Kim (Mechanical engineer)

Sunmin Hwang (Electronic engineer)

Seungcheol Lee (Post-doctor)

SSS beamline – RSXS endstation :

Hoyoung Jang (PhD. Beamline staff)

Thank you for your attention!